## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination FANG ET AL. Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0124572	07-2003	Umek et al.	435/6
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